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Search Results - Record(s) 1 through 4 of 4 returned.

☑ 1. Document ID: US 5493729 A

Using default format because multiple data bases are involved.

L15: Entry 1 of 4

File: USPT

Feb 20, 1996

US-PAT-NO: 5493729

DOCUMENT-IDENTIFIER: US 5493729 A

TITLE: Knowledge data base processing system and expert system

DATE-ISSUED: February 20, 1996

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Nigawara; Seiitsu Hitachi JP Namba; Shigeaki Hitachi JP Kohmoto; Hiroshi Hitachi JP

US-CL-CURRENT: <u>706/52</u>; <u>706/60</u>

| Full Title | Citation | Front | Review | Classification | Date | Reference | Samenas Alechnens | Claims | KMC | Draw, De |
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☑ 2. Document ID: US 5005143 A

L15: Entry 2 of 4 File: USPT Apr 2, 1991

US-PAT-NO: 5005143

DOCUMENT-IDENTIFIER: US 5005143 A

TITLE: Interactive statistical system and method for predicting expert decisions

DATE-ISSUED: April 2, 1991

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Altschuler; Martin D. Wallingford PA Whittington; Richard Media PA

US-CL-CURRENT: 702/181; 706/46, 706/52, 706/924

Record List Display Page 2 of 3

Full Title Citation Front Review Classification Date Reference Company Misching Claims KMC Draw, De

☐ 3. Document ID: DE 4108310 A, JP 3268529 B2, US 5493729 A, DE 4108310 C2

L15: Entry 3 of 4

File: DWPI

Sep 26, 1991

DERWENT-ACC-NO: 1991-289202

DERWENT-WEEK: 200222

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TITLE: Knowledge base processing and expert system - stores indices representing certainty grade of casual relationship between occurrence and others relevant to it

INVENTOR: KOHMOTO, H; NAMBA, S; NIGAWARA, S

PRIORITY-DATA: 1990JP-0063697 (March 14, 1990)

PATENT-FAMILY:

| PUB-NO | PUB-DATE | LANGUAGE | PAGES | MAIN-IPC |
|---------------|--------------------|----------|-------|------------|
| DE 4108310 A | September 26, 1991 | | 000 | |
| JP 3268529 B2 | March 25, 2002 | | 019 | G06F009/44 |
| US 5493729 A | February 20, 1996 | | 023 | G06F015/18 |
| DE 4108310 C2 | October 22, 1998 | | 000 | G06F015/18 |

INT-CL (IPC): G06F 9/44; G06F 15/18

| Full | Title | Citation | Front | Review | Classification | Date | Reference | 7775 | Attackment | Claims | KMC | Draw, De |
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☐ 4. Document ID: US 5005143 A

L15: Entry 4 of 4

File: DWPI

Apr 2, 1991

DERWENT-ACC-NO: 1991-117187

DERWENT-WEEK: 199116

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TITLE: Interactive statistical system and predicting expert decisions - repeating random value generation and corresponding responses until sufficient are given to

achieve set statistical significance

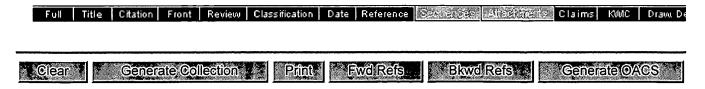
PRIORITY-DATA: 1989US-0411911 (September 25, 1989), 1987US-0065304 (June 19, 1987)

PATENT-FAMILY:

PUB-NO PUB-DATE LANGUAGE PAGES MAIN-IPC

US 5005143 A April 2, 1991 000

INT-CL (IPC): G06F 9/00; G06F 15/42



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| (5,005,143 5,493,729).pn. | 4 |

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| (5,005,143 5,493,729).pn. | 4 | | | |

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| <u>L13</u> | L12 and bayesian | 63 | <u>L13</u> |
| <u>L12</u> | diagnostic adj systems | 3451 | <u>L12</u> |
| <u>L11</u> | L10 and sequence and resolution | 7 | <u>L11</u> |
| <u>L10</u> | diagnostic adj model | 85 | <u>L10</u> |
| <u>L9</u> | probabil\$6 and troubleshooters and diagnostics | 2 | <u>L9</u> |
| <u>L8</u> | L4 and probabil\$6 and troubleshoot and diagnostics | 3 | <u>L8</u> |
| <u>L7</u> | L4 and probabil\$6 and debug and diagnos\$6 | 9 | <u>L7</u> |
| <u>L6</u> | L4 and probabil\$6 and diagnos\$6 | 54 | <u>L6</u> |
| <u>L5</u> | L4 and probabil\$6 and troubleshooters and diagnostics | 0 | <u>L5</u> |
| <u>L4</u> | 706/52.ccls. | 393 | <u>L4</u> |
| <u>L3</u> | 6,456,622.pn. | 2 | <u>L3</u> |
| <u>L2</u> | 4,866,635.pn. | 2 | <u>L2</u> |

<u>L1</u> 6,535,865.pn.

2 <u>L1</u>

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Record List Display Page 1 of 2

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Search Results - Record(s) 1 through 2 of 2 returned.

☐ 1. Document ID: US 5133046 A

Using default format because multiple data bases are involved.

L16: Entry 1 of 2

File: USPT

Jul 21, 1992

US-PAT-NO: 5133046

DOCUMENT-IDENTIFIER: US 5133046 A

TITLE: Computer-based diagnostic expert system organized according to Bayesian

theory

DATE-ISSUED: July 21, 1992

INVENTOR-INFORMATION:

NAME CITY

CITY STATE ZIP CODE COUNTRY

Kaplan; Stanley Rancho Palas Verdes

CA

US-CL-CURRENT: 706/52; 706/912, 706/914

Full Title Citation Front Review Classification Date Reference Sequences Attendents Claims KMC Draw De

☐ 2. Document ID: US 5133046 A

L16: Entry 2 of 2

File: DWPI

Jul 21, 1992

DERWENT-ACC-NO: 1992-268277

DERWENT-WEEK: 199232

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TITLE: Computer-based diagnostic expert system organised according to bayesian theory - generates diagnosis in form of probability distributions, responding to

evidence in discrete time trajectories and data from knowledge base

INVENTOR: KAPLAN, S

PRIORITY-DATA: 1991US-0637190 (January 3, 1991)

PATENT-FAMILY:

PUB-NO PUB-DATE LANGUAGE PAGES MAIN-IPC

<u>US 5133046 A</u> July 21, 1992 022 G06F015/18

INT-CL (IPC): G06F 15/18

| Full | Title | Citation | Front | Review | Classification | Date | Reference | Sequence | 3 | rigents | Claims | KWIC | Draw, De |
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| Terms | Documents |
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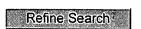
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| <u>L12</u> | diagnostic adj systems | 3451 | <u>L12</u> |
| <u>L11</u> | L10 and sequence and resolution | 7 | <u>L11</u> |
| <u>L10</u> | diagnostic adj model | 85 | <u>L10</u> |
| <u>L9</u> | probabil\$6 and troubleshooters and diagnostics | 2 | <u>L9</u> |
| <u>L8</u> | L4 and probabil\$6 and troubleshoot and diagnostics | 3 | <u>L8</u> |
| <u>L7</u> | L4 and probabil\$6 and debug and diagnos\$6 | 9 | <u>L7</u> |
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| <u>L5</u> | L4 and probabil\$6 and troubleshooters and diagnostics | 0 | <u>L5</u> |
| <u>L4</u> | 706/52.ccls. | 393 | <u>L4</u> |
| <u>L3</u> | 6,456,622.pn. | 2 | <u>L3</u> |
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| O- Advanced | 2 Decision-theoretic case-based reasoning Breese, J.S.; Heckerman, D.; | |
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[Abstract] [PDF Full-Text (552KB)] IEEE JNL

3 Causal independence for probability assessment and inference using **Bayesian networks**

Heckerman, D.; Breese, J.S.;

Systems, Man and Cybernetics, Part A, IEEE Transactions on ,Volume: 26 , I 6, Nov. 1996

Pages:826 - 831

[Abstract] [PDF Full-Text (604KB)] IEEE JNL

4 An approximate nonmyopic computation for value of information

Heckerman, D.; Horvitz, E.; Middleton, B.;

Pattern Analysis and Machine Intelligence, IEEE Transactions on ,Volume: 15 , Issue: 3 , March 1993

Pages: 292 - 298

[Abstract] [PDF Full-Text (604KB)] IEEE JNL

5 Separating appearance from deformation

Jojic, N.; Simard, P.; Frey, B.J.; Heckerman, D.; Computer Vision, 2001. ICCV 2001. Proceedings. Eighth IEEE International Conference on ,Volume: 2 , 7-14 July 2001

Pages: 288 - 294 vol. 2

[Abstract] [PDF Full-Text (788KB)] IEEE CNF

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| <u>L10</u> | diagnostic adj model | 85 | <u>L10</u> |
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| <u>L8</u> | L4 and probabil\$6 and troubleshoot and diagnostics | 3 | <u>L8</u> |
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| <u>L6</u> | L4 and probabil\$6 and diagnos\$6 | 54 | <u>L6</u> |
| <u>L5</u> | L4 and probabil\$6 and troubleshooters and diagnostics | 0 | <u>L5</u> |
| <u>L4</u> | 706/52.ccls. | 393 | <u>L4</u> |
| <u>L3</u> | 6,456,622.pn. | 2 | <u>L3</u> |
| <u>L2</u> | 4,866,635.pn. | 2 | <u>L2</u> |
| <u>L1</u> | 6,535,865.pn. | 2 | <u>L1</u> |

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☐ 1. Document ID: US 5751915 A

Using default format because multiple data bases are involved.

L7: Entry 1 of 9

File: USPT

May 12, 1998

US-PAT-NO: 5751915

DOCUMENT-IDENTIFIER: US 5751915 A

TITLE: Elastic fuzzy logic system

DATE-ISSUED: May 12, 1998

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE

Werbos; Paul J. College Park MD 20740

US-CL-CURRENT: 706/4; 706/2, 706/52

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KWC Draw. De

☐ 2. Document ID: US 5604841 A

L7: Entry 2 of 9

File: USPT

Feb 18, 1997

COUNTRY

US-PAT-NO: 5604841

DOCUMENT-IDENTIFIER: US 5604841 A

TITLE: Hierarchical restructuring generic test templates and reusable value spaces

for machine failure isolation using qualitative physics

DATE-ISSUED: February 18, 1997

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Hamilton; Thomas P. South Windsor CT Clark; Robert T. Enfield CT

Gallo; Steven Vernon CT

US-CL-CURRENT: 706/11; 706/52

☐ 3. Document ID: US 5537644 A

L7: Entry 3 of 9

File: USPT

Jul 16, 1996

US-PAT-NO: 5537644

DOCUMENT-IDENTIFIER: US 5537644 A

TITLE: Machine failure isolation in multiple machine configurations using

qualitative physics

DATE-ISSUED: July 16, 1996

INVENTOR-INFORMATION:

CITY STATE ZIP CODE COUNTRY

Hamilton; Thomas P.

South Windsor

CT

Clark; Robert T.

Enfield

US-CL-CURRENT: <u>706/52</u>; <u>702/33</u>, <u>702/35</u>

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KMC Draw. De

☐ 4. Document ID: US 5522014 A

L7: Entry 4 of 9

File: USPT

May 28, 1996

US-PAT-NO: 5522014

DOCUMENT-IDENTIFIER: US 5522014 A

** See image for Certificate of Correction **

TITLE: Intergrated qualitative/quantitative reasoning with enhanced core predictions and extended test procedures for machine failure isolation using qualitative physics

DATE-ISSUED: May 28, 1996

INVENTOR-INFORMATION:

NAME CITY

STATE ZIP CODE COUNTRY

Clark; Robert T.

Enfield

CT

Hamilton; Thomas P.

South Windsor

CT

Gallo; Steven

Vernon

CT

US-CL-CURRENT: 706/45; 702/17, 706/52, 706/911, 706/912

Full Title Citation Front Review Classification Date Reference Societies Attaclinents Claims KWIC Draw, De

☐ 5. Document ID: US 5353381 A

L7: Entry 5 of 9

File: USPT

Oct 4, 1994

US-PAT-NO: 5353381

DOCUMENT-IDENTIFIER: US 5353381 A

TITLE: Intelligent test selection for machine failure isolation using qualitative

physics

DATE-ISSUED: October 4, 1994

INVENTOR-INFORMATION:

NAME

CITY

STATE ZIP CODE

COUNTRY

Hamilton; Thomas P.

Monroe

South Windsor

CTCT

Perveiler; Kevin J. Jacobsen; Carol E.

Shelton

CT

US-CL-CURRENT: 706/52

Full Title Citation Front Review Classification Date Reference Sequences Stationing Claims KMC Draw De

☐ 6. Document ID: US 5216749 A

L7: Entry 6 of 9

File: USPT

Jun 1, 1993

US-PAT-NO: 5216749

DOCUMENT-IDENTIFIER: US 5216749 A

TITLE: Core predictions for qualitative physics

DATE-ISSUED: June 1, 1993

INVENTOR-INFORMATION:

NAME

CITY

ZIP CODE STATE

COUNTRY

Hamilton; Thomas P.

South Windsor

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912, 706/913

Full Title Citation Front Review Classification Date Reference Societies Attachments Claims KMC Draw, De

☐ 7. Document ID: US 5202955 A

L7: Entry 7 of 9

File: USPT

Apr 13, 1993

US-PAT-NO: 5202955

DOCUMENT-IDENTIFIER: US 5202955 A

TITLE: Dynamic assumption ordering for qualitative physics

DATE-ISSUED: April 13, 1993

INVENTOR-INFORMATION:

NAME

CITY

STATE ZIP CODE

COUNTRY

· Record List Display Page 4 of 5

Hamilton; Thomas P.

South Windsor

CT

Jacobsen; Carol E.

Shelton

CT

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912, 706/913

Full Title Citation Front Review Classification Date Reference Structures Attachments Claims KMC Draw De

□ 8. Document ID: US 5187773 A

L7: Entry 8 of 9

File: USPT

Feb 16, 1993

US-PAT-NO: 5187773

DOCUMENT-IDENTIFIER: US 5187773 A

** See image for Certificate of Correction **

TITLE: Machine failure isolation using qualitative physics

DATE-ISSUED: February 16, 1993

INVENTOR-INFORMATION:

CITY

STATE

COUNTRY

Hamilton; Thomas P.

South Windsor

CT

Jacobsen; Carol E.

Shelton

CT

Perveiler; Kevin J.

Monroe

CT

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912

Full Title Citation Front Review Classification Date Reference Secretics (2005) 2005 Propriet Claims KMC Draw De

☐ 9. Document ID: US 5138694 A

L7: Entry 9 of 9

File: USPT

Aug 11, 1992

US-PAT-NO: 5138694

DOCUMENT-IDENTIFIER: US 5138694 A

TITLE: Parallel processing qualitative reasoning system

DATE-ISSUED: August 11, 1992

INVENTOR-INFORMATION:

NAME CITY STATE

ZIP CODE

ZIP CODE

COUNTRY

Hamilton; Thomas P.

South Windosr

CT

US-CL-CURRENT: 706/52; 706/10

Full Title Citation Front Review Classification Date Reference Security 2 Attachments Claims KMC Draw De

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Search Results - Record(s) 1 through 3 of 3 returned.

☐ 1. Document ID: US 5604841 A

Using default format because multiple data bases are involved.

L8: Entry 1 of 3

File: USPT

Feb 18, 1997

US-PAT-NO: 5604841

DOCUMENT-IDENTIFIER: US 5604841 A

TITLE: Hierarchical restructuring generic test templates and reusable value spaces

for machine failure isolation using qualitative physics

DATE-ISSUED: February 18, 1997

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Hamilton; Thomas P. South Windsor CT Clark; Robert T. Enfield CT

Gallo; Steven Vernon CI

US-CL-CURRENT: 706/11; 706/52



☐ 2. Document ID: US 5537644 A

L8: Entry 2 of 3

File: USPT

Jul 16, 1996

US-PAT-NO: 5537644

DOCUMENT-IDENTIFIER: US 5537644 A

TITLE: Machine failure isolation in multiple machine configurations using

qualitative physics

DATE-ISSUED: July 16, 1996

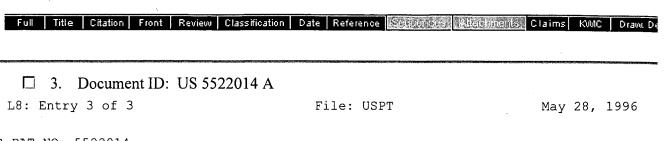
INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Hamilton; Thomas P. South Windsor CT

Clark; Robert T. Enfield CT

US-CL-CURRENT: 706/52; 702/33, 702/35



US-PAT-NO: 5522014

DOCUMENT-IDENTIFIER: US 5522014 A

** See image for Certificate of Correction **

TITLE: Intergrated qualitative/quantitative reasoning with enhanced core predictions and extended test procedures for machine failure isolation using qualitative physics

DATE-ISSUED: May 28, 1996

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Clark; Robert T. Enfield CT Hamilton; Thomas P. South Windsor CT

Gallo; Steven Vernon CT

US-CL-CURRENT: 706/45; 702/17, 706/52, 706/911, 706/912

| Full Title Citation Front | Review Classification | Date Reference | STATE STATE | Claims | KWIC | Draw, Di |
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Search Results - Record(s) 1 through 2 of 2 returned.

☐ 1. Document ID: US 20020116351 A1

Using default format because multiple data bases are involved.

L9: Entry 1 of 2

File: PGPB

Aug 22, 2002

PGPUB-DOCUMENT-NUMBER: 20020116351

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020116351 A1

TITLE: Methods and structure for characterization of bayesian belief networks

PUBLICATION-DATE: August 22, 2002

INVENTOR-INFORMATION:

NAME

CITY

STATE

COUNTRY RULE-47

Skaanning, Claus

Dronninglund

CO

DK

Wright, David W.

Fort Collins

US

US-CL-CURRENT: 706/21

| F 0 | Title | Citation | F | Daniero | Classification | DA. | Distance | Sagriagas | Attachments | السينيات ا | 10010 | D D |
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☐ 2. Document ID: US 6012152 A

L9: Entry 2 of 2

File: USPT

Jan 4, 2000

COUNTRY

US-PAT-NO: 6012152

DOCUMENT-IDENTIFIER: US 6012152 A

** See image for <u>Certificate of Correction</u> **

TITLE: Software fault management system

DATE-ISSUED: January 4, 2000

INVENTOR-INFORMATION:

NAME CITY

Y STATE ZIP CODE

Douik; Samir Sainte Anne de Bellevue CA

Boutaba; Raouf Montreal CA

US-CL-CURRENT: 714/26

| Full | Title | Citation | Front | Review | Classification | Date | Reference | Secure 1 | | Claims | KWIC | Draw |
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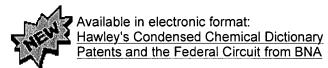
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(Database of examiner submitted NPL)

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(EPO's databases, available on stand-alone terminal in CPK2, 4B40)

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Research Disclosure

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(The other link is via the Patent Examiner's Toolkit. On your computer, click on the START button, then on the PE Toolkit, then on STN Express.)

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(Dictionaries, Acronyms Finders, Encyclopedias)

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(30,000 pages of engineering fundamentals and calculators)

Encyclopedia Britannica

Eric Weisstein's World of Mathematics

(A comprehensive online encyclopedia of mathematics.)

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(Search a term to find articles that explain how it works.)

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A Brief History of the Hard Disk Drive

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(Full text scientific research papers - in pdf and postscript formats.)

Internet Engineering Task Force

(The IETF Secretariat, run by The Corporation for National Research Initiatives with funding from the US government, maintains an index of Internet-Drafts.)

Nanotechnology Requests for Comments (RFCs) Database

(Requests for Comments (RFC) document series is a set of technical and organizational notes about the Internet (originally the ARPANET), beginning in 1969 and discussing

many

aspects of computer networking, including protocols, procedures and concepts as well as meeting notes and opinions.)

- Usenet Archive (Google Groups)
- Wayback Machine (Archived web pages.)

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| <u>L13</u> | L12 and bayesian | 63 | <u>L13</u> |
| <u>L12</u> | diagnostic adj systems | 3451 | <u>L12</u> |
| <u>L11</u> | L10 and sequence and resolution | 7 | <u>L11</u> |
| <u>L10</u> | diagnostic adj model | 85 | <u>L10</u> |
| <u>L9</u> | probabil\$6 and troubleshooters and diagnostics | 2 | <u>L9</u> |
| <u>L8</u> | L4 and probabil\$6 and troubleshoot and diagnostics | 3 | <u>L8</u> |
| <u>L7</u> | L4 and probabil\$6 and debug and diagnos\$6 | 9 | <u>L7</u> |
| <u>L6</u> | L4 and probabil\$6 and diagnos\$6 | 54 | <u>L6</u> |
| <u>L5</u> | L4 and probabil\$6 and troubleshooters and diagnostics | 0 | <u>L5</u> |
| <u>L4</u> | 706/52.ccls. | 393 | <u>L4</u> |
| <u>L3</u> | 6,456,622.pn. | 2 | <u>L3</u> |
| <u>L2</u> | 4,866,635.pn. | 2 | <u>L2</u> |
| <u>L1</u> | 6,535,865.pn. | 2 | <u>L1</u> |

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Record List Display Page 1 of 8

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Search Results - Record(s) 1 through 16 of 16 returned.

☐ 1. Document ID: US 20030167111 A1

Using default format because multiple data bases are involved.

L14: Entry 1 of 16

File: PGPB

Sep 4, 2003

PGPUB-DOCUMENT-NUMBER; 20030167111

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20030167111 A1

TITLE: Diagnostic system and method

PUBLICATION-DATE: September 4, 2003

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY RULE-47 Kipersztok, Oscar Redmond WA US Rein-Weston, Karl J. Seattle WA US Nelson, Scott L. Issaguah WA US Dildy, Glenn A. Sammamish WA US Chew, Susan Chan Issaquah WA US

US-CL-CURRENT: 701/29; 702/185, 714/25

| Full | Title | Citation | Front | Review | Classification | Date | Reference | Sequences | Attachments | Claims | KWIC | Draw, De |
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☐ 2. Document ID: US 20020183988 A1

L14: Entry 2 of 16

File: PGPB

Dec 5, 2002

PGPUB-DOCUMENT-NUMBER: 20020183988

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020183988 A1

TITLE: Model selection for decision support systems

PUBLICATION-DATE: December 5, 2002

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY RULE-47

Skaanning, Claus Dronninglund CO DK Schreckengast, James Fort Collins US Record List Display Page 2 of 8

US-CL-CURRENT: 703/2

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KWC Draw. De

☐ 3. Document ID: US 20020138184 A1

L14: Entry 3 of 16

File: PGPB

Sep 26, 2002

PGPUB-DOCUMENT-NUMBER: 20020138184

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020138184 A1

TITLE: Diagnostic system and method

PUBLICATION-DATE: September 26, 2002

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY RULE-47

Kipersztok, Oscar Redmond WA US Rein-Weston, Karl J. Seattle WA US Walker, Nicholas James WA US Seattle Chew, Susan Chan Issaquah WA US

US-CL-CURRENT: 701/29; 340/945

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KWC Draw, De

☐ 4. Document ID: US 20020116351 A1

L14: Entry 4 of 16

File: PGPB

Aug 22, 2002

PGPUB-DOCUMENT-NUMBER: 20020116351

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020116351 A1

TITLE: Methods and structure for characterization of bayesian belief networks

PUBLICATION-DATE: August 22, 2002

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY RULE-47

Skaanning, Claus Dronninglund CO DK Wright, David W. Fort Collins US

US-CL-CURRENT: 706/21

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KMC Draw. De

Record List Display Page 3 of 8

□ 5. Document ID: US 20020044296 A1

L14: Entry 5 of 16 File: PGPB Apr 18, 2002

PGPUB-DOCUMENT-NUMBER: 20020044296

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020044296 A1

TITLE: Authoring tool for bayesian network diagnostic systems

PUBLICATION-DATE: April 18, 2002

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY RULE-47

Skaanning, Claus Dronninglund DK

US-CL-CURRENT: 358/1.14; 358/1.15

| Full T | itle Citation | Front | Review | Classification | Date | Reference | Sequences | Attachments | Claims | KWIC | Draw, De |
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☐ 6. Document ID: US 20010011260 A1

L14: Entry 6 of 16 File: PGPB

Aug 2, 2001

PGPUB-DOCUMENT-NUMBER: 20010011260

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20010011260 A1

TITLE: Automated diagnosis of printer systems using bayesian networks

PUBLICATION-DATE: August 2, 2001

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY RULE-47 Dronninglund Skaanning, Claus ID DK Jensen, Finn V. Broenderslev ΙD DK Kjaerulff, Uffe Aalborg DK Pelletier, Paul A. US Boise Jensen, Lasse Rostrup Aalborg DK Parker, Marilyn A. Boise US Bogorad, Janice L. Allerod DK

US-CL-CURRENT: 706/46

□ 7. Document ID: US 6591257 B1

L14: Entry 7 of 16 ·

File: USPT

Jul 8, 2003

Record List Display Page 4 of 8

US-PAT-NO: 6591257

DOCUMENT-IDENTIFIER: US 6591257 B1

TITLE: Apparatus and method for a compositional decision support reasoning system

DATE-ISSUED: July 8, 2003

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Martinka; Joseph J Sunnyvale CA
Collins; Patricia Mountain View CA
Forman; George H. Port Orchard WA
Kirshenbaum; Evan R. Mountain View CA
Seetharaman; Aparna Palo Alto CA

US-CL-CURRENT: <u>706/46</u>

| Full | Title | Citation | Front | Review | Classification | Date | Reference | Secretaria es | Gustaments | Claims | KWIC | Draw, De |
|------|-------|----------|-------|--------|----------------|------|-----------|---------------|------------|--------|------|----------|
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☐ 8. Document ID: US 6574537 B2

L14: Entry 8 of 16 File: USPT

Jun 3, 2003

US-PAT-NO: 6574537

DOCUMENT-IDENTIFIER: US 6574537 B2

TITLE: Diagnostic system and method

DATE-ISSUED: June 3, 2003

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Kipersztok; Oscar Redmond WA Rein-Weston; Karl J. Seattle WA Nelson; Scott L. WA Issaquah Dildy; Glenn A. Sammamish WA Walker; Nicholas James Seattle WA Chew; Susan Chan Issaquah WA

US-CL-CURRENT: 701/29; 701/33, 701/34, 702/185, 714/25

| Full | Title | Citation | Front | Review | Classification | Date | Reference | 100 | Mark Telephone | Claims | KWC | Draw, De |
|------|-------|----------|-------|--------|----------------|------|-----------|-----|----------------|--------|-----|----------|
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☐ 9. Document ID: US 6484010 B1

L14: Entry 9 of 16

File: USPT

Nov 19, 2002

US-PAT-NO: 6484010

DOCUMENT-IDENTIFIER: US 6484010 B1

** See image for Certificate of Correction **

Record List Display Page 5 of 8

TITLE: Tree-based approach to proficiency scaling and diagnostic assessment

DATE-ISSUED: November 19, 2002

INVENTOR-INFORMATION:

NAME

CITY

STATE ZIP CODE

COUNTRY

Sheehan; Kathleen M.

Skillman

NJ

US-CL-CURRENT: 434/362; 434/118, 434/322, 434/350

| Full Title Citation Front R | eview Classification | Date Reference | Saturancias 20 ochonents | Claims | KMC | Draw De |
|-----------------------------|----------------------|----------------|--------------------------|---|-----|---------|
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| ☐ 10. Document ID: | US 6394952 B1 | | | ,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,, | - | |
| L14: Entry 10 of 16 | | File: | USPT | May 2 | 28, | 2002 |

US-PAT-NO: 6394952

DOCUMENT-IDENTIFIER: US 6394952 B1

** See image for Certificate of Correction **

TITLE: Point of care diagnostic systems

DATE-ISSUED: May 28, 2002

INVENTOR-INFORMATION:

| NAME | CITY | STATE | ZIP CODE COUNTRY |
|--------------------|--------------|-------|------------------|
| Anderson; Emory V. | Danville | CA | |
| Lapointe; Jerome | Oakland | CA | |
| Martinez; Ricardo | Santa Cruz | CA | |
| Marzolf; Gail | Cupertino | CA | |
| Pong; Ronald | San Jose | CA | |
| Jones; Lynn | Mountainview | CA | |
| Hussa; Robert O. | Sunnyvale | CA | |
| Nemec; Edward | Duluth | GA | |
| Senyei; Andrew E. | La Jolla | CA | |
| DeSieno; Duane | La Jolla | CA | |
| | | | |

US-CL-CURRENT: 600/300; 435/4, 436/814, 600/304, 600/310, 600/351, 600/573, 600/584

| Full Title Citation | Front Review Clas | sification Date Reference | Seattenner Attachmenia | Claims KWC Draw, De |
|---------------------|-------------------|---------------------------|------------------------|---------------------|
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☐ 11. Document ID: US 6267722 B1

L14: Entry 11 of 16

File: USPT

Jul 31, 2001

US-PAT-NO: 6267722

DOCUMENT-IDENTIFIER: US 6267722 B1

** See image for Certificate of Correction **

Record List Display Page 6 of 8

TITLE: Point of care diagnostic systems

DATE-ISSUED: July 31, 2001

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Danville CA Anderson; Emory V. Nemec; Edward Duluth GΑ Oakland CA Lapointe; Jerome CA DeSieno; Duane La Jolla Santa Cruz Martinez; Ricardo CA CA Marzolf; Gail Cupertino CA

Pong; Ronald San Jose CA
Jones; Lynn Mountain View CA
Hussa; Robert O. Sunnyvale CA

Senyei; Andrew E. La Jolla CA

US-CL-CURRENT: $\underline{600}/\underline{300}$; $\underline{435}/\underline{4}$, $\underline{436}/\underline{811}$, $\underline{436}/\underline{814}$, $\underline{600}/\underline{304}$, $\underline{600}/\underline{310}$, $\underline{600}/\underline{345}$, $\underline{600}/\underline{573}$, $\underline{600}/\underline{584}$

Full Title Citation Front Review Classification Date Reference <u>Sequences Attactiments</u> Claims KWC Draw. De

☐ 12. Document ID: US 6219626 B1

L14: Entry 12 of 16

File: USPT

Apr 17, 2001

US-PAT-NO: 6219626

DOCUMENT-IDENTIFIER: US 6219626 B1

** See image for <u>Certificate of Correction</u> **

TITLE: Automated diagnostic system

DATE-ISSUED: April 17, 2001

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Steinmetz; Michael J. Kissimmee FL 34743 Kirst; Michael E. Kissimmee FL 34744

US-CL-CURRENT: 702/183; 702/182, 702/185, 714/25, 714/46

Full Title Citation Front Review Classification Date Reference Section 2007 (Street Field) Claims KWC Draw De

☐ 13. Document ID: US 6144838 A

L14: Entry 13 of 16 File: USPT Nov 7, 2000

US-PAT-NO: 6144838

DOCUMENT-IDENTIFIER: US 6144838 A

Record List Display Page 7 of 8

TITLE: Tree-based approach to proficiency scaling and diagnostic assessment

DATE-ISSUED: November 7, 2000

INVENTOR-INFORMATION:

NAME

CITY

STATE

ZIP CODE COUNTRY

Sheehan; Kathleen M.

Skillman

NJ

US-CL-CURRENT: 434/362; 434/118, 434/322, 434/350

| Full | Title | Citation | Front | Review | Classification | Date | Reference | Sestimate Startments | Claims | KWC | Draw, De |
|-------------|-------|----------|-------|--------|----------------|------|-----------|----------------------|--------|-----|----------|
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☑ 14. Document ID: US 6076083 A

L14: Entry 14 of 16

File: USPT

Jun 13, 2000

US-PAT-NO: 6076083

DOCUMENT-IDENTIFIER: US 6076083 A

TITLE: Diagnostic system utilizing a Bayesian network model having link weights

updated experimentally

DATE-ISSUED: June 13, 2000

INVENTOR-INFORMATION:

NAME

CITY

STATE

ZIP CODE

COUNTRY

Baker; Michelle

New York

NY

10025

US-CL-CURRENT: 706/52; 706/45, 706/46, 706/61

| Full | Title Citation | Front Re | view Classificatio | n Date | Reference | 1500 | Claims | KWIC | Drawi De |
|------|----------------|-----------|----------------------|--------|------------|------|--------|------|-------------------------------------|
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| | 15. Docum | ent ID: U | JS 5544308 <i>A</i> | 1 | | | | | |
| L14: | Entry 15 of | 16 | | | File: USPT | | Aug | 6, | 1996 |

US-PAT-NO: 5544308

DOCUMENT-IDENTIFIER: US 5544308 A

TITLE: Method for automating the development and execution of diagnostic reasoning

software in products and processes

DATE-ISSUED: August 6, 1996

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY Giordano; Gerard J. Sparta NJ deMare; Gregory Sparta NJ Longendorfer; Betsy Ridgewood NJ Granieri; Michael N. Springfield VA

Record List Display Page 8 of 8

Giordano; John P.

Sparta

NJ

Nolan; Mary E.

Lafayette

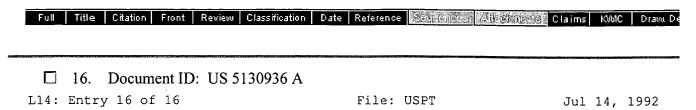
NJ

Levy; Ford

Pleasantville

NY

US-CL-CURRENT: <u>714/26</u>; <u>706/45</u>, <u>706/912</u>



US-PAT-NO: 5130936

DOCUMENT-IDENTIFIER: US 5130936 A

TITLE: Method and apparatus for diagnostic testing including a neural network for

determining testing sufficiency

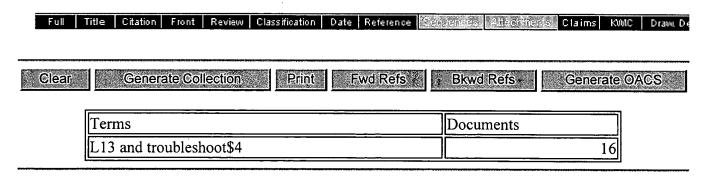
DATE-ISSUED: July 14, 1992

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Sheppard; John W. Glen Burnie MD Simpson; William R. Edgewater MD Graham; Jerry L. Baldwin MD

US-CL-CURRENT: 702/123; 128/925, 324/73.1, 706/10, 706/20, 706/911



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| - By Author - Basic - Advanced Member Services | <i>Przytula, K</i> Aerospace | (.W.; Thompson, D | networks for diagnos .; edings, 2000 IEEE , Volum | |
| O- Join IEEE O- Establish IEEE | [Abstract] | [PDF Full-Text (| 588 KB)] IEEE CNF | |
| Web Account - Access the IEEE Member Digital Library | and partia Nikovski, D | ally correct statis D.; e and Data Enginee ig. 2000 | etworks for medical distics ring, IEEE Transactions o | · |
| | [Abstract] | [PDF Full-Text (| 160 KB)] IEEE JNL | |
| | Schwall, M. American (May 2002 | J.L.; Gerdes, J.C.; Control Conference 2 - 2557 vol.3 | to residual processing, 2002. Proceedings of the | |
| | <i>Das, B.; Ba</i> Bioenginee | <i>anerjee, S.;</i> ering Conference, 2 , 20-21 April 2002 | em for Doppler ultrason | |

[Abstract] [PDF Full-Text (333 KB)] **IEEE CNF**

5 Extending the feature dictionary t support sophisticated feature interaction and classification

Samuels, W.B.; Evens, M.; Naeymi-Rad, F.; Rosenthal, R.; Naeymirad, S.; Le Trace, D.; Carmony, L.;

Computer-Based Medical Systems, 1989. Proceedings., Second Annual IEEE Symposium on , 26-27 June 1989

Pages:29 - 35

[Abstract] [PDF Full-Text (524 KB)] **IEEE CNF**

6 Summary and applicability of analog fault detection/isolation techn

AUTOTESTCON '97. 1997 IEEE Autotestcon Proceedings , 22-25 Sept. 1997 Pages:383 - 389

[Abstract] [PDF Full-Text (608 KB)]

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